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1:1 14-bit SSTL_2 Registered Buffer



ADE-205-695 (Z)

Rev.0 Jun. 2002

Description

The HD74SSTV16857A is a 14-bit registered buffer designed for 2.3 V to 2.7 V Vcc operation and LVCMOS reset (\overline{RESET}) input / SSTL_2 data (D) inputs and CLK input.

Data flow from D to Q is controlled by differential clock pins (CLK, $\overline{\text{CLK}}$) and the $\overline{\text{RESET}}$. Data is triggered on the positive edge of the positive clock (CLK), and the negative clock ($\overline{\text{CLK}}$) must be used to maintain noise margins. When $\overline{\text{RESET}}$ is low, all registers are reset and all outputs are low.

To ensure defined outputs from the register before a stable clock has been supplied, \overline{RESET} must be held in the low state during power up.

Features

- Supports LVCMOS reset (RESET) input / SSTL_2 data (D) inputs and CLK input
- Differential SSTL_2 (Stub series terminated logic) CLK signal
- Flow through architecture optimizes PCB layout
- · Package type

Package type	Package code	Package suffix	Taping code
TSSOP-48 pin	TTP-48DBV	T	EL (1,000 pcs / Reel)
TVSOP-48 pin	TTP-48DEV	N	EL (1,000 pcs / Reel)

Function Table

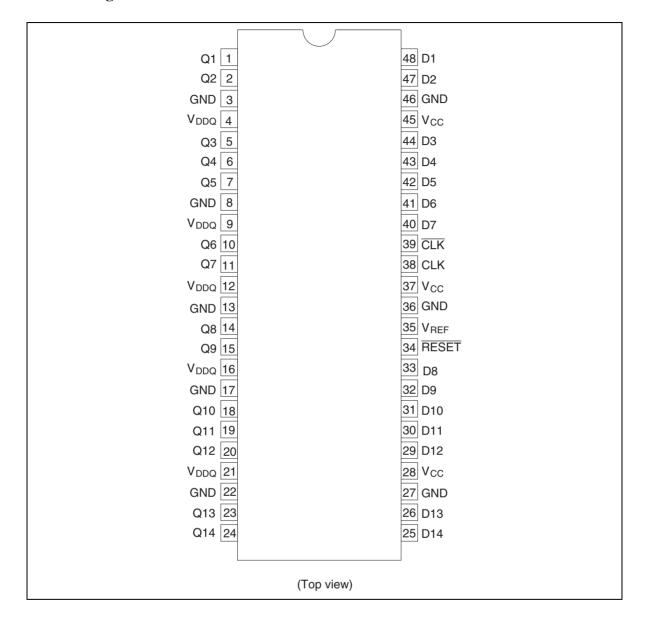
Inputs		Output Q		
RESET	CLK	CLK	D	
L	Х	Х	Х	L
Н	\	1	Н	Н
Н	\	1	L	L
Н	L or H	H or L	Х	Q ₀ *1

H: High level
L: Low level
X: Immaterial

↑: Low to high transition ↓: High to low transition

Note: 1. Output level before the indicated steady state input conditions were established.

Pin Arrangement



Absolute Maximum Ratings

Item	Symbol	Ratings	Unit	Conditions
Supply voltage	V _{CC} or V _{DDQ}	-0.5 to 3.6	V	
Input voltage *1	V,	-0.5 to V _{DDQ} +0.5	V	
Output voltage *1, 2	V _o	-0.5 to V _{DDQ} +0.5	V	
Input clamp current	I _{IK}	±50	mA	$V_{l} < 0 \text{ or } V_{l} > V_{CC}$
Output clamp current	I _{ok}	±50	mA	$V_{o} < 0 \text{ or } V_{o} > V_{DDQ}$
Continuous output current	I _o	±50	mA	$V_{o} = 0 \text{ to } V_{DDQ}$
$\overline{V_{\text{CC}}, V_{\text{DDQ}}}$ or GND current / pin	I_{CC} , I_{DDQ} or I_{GND}	±100	mA	
Maximum power dissipation at Ta = 55°C (in still air)	P _T	115	°C / W	TSSOP
Storage temperature	Tstg	-65 to +150	°C	

Notes:

Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute maximum rated conditions for extended periods may affect device reliability.

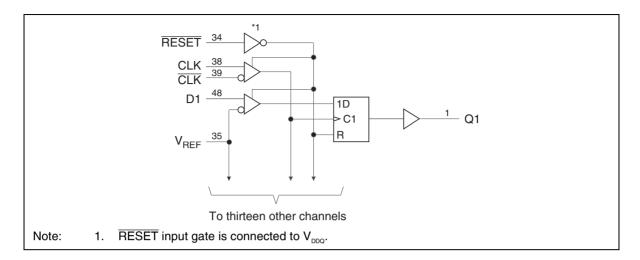
- 1. The input and output negative voltage ratings may be exceeded if the input and output clamp current ratings are observed.
- 2. This current will flow only when the output is in the high state and $V_o > V_{\tiny DDO}$.

Recommended Operating Conditions

Item		Symbol	Min	Тур	Max	Unit	Conditions
Supply voltage	ge	V _{cc}	$V_{\scriptscriptstyle DDQ}$	2.5	2.7	V	_
Output suppl	y voltage	V _{DDQ}	2.3	2.5	2.7	V	
Reference vo	oltage	V _{REF}	1.15	1.25	1.35	V	$V_{\text{REF}} = 0.5 \times V_{\text{DDQ}}$
Termination		V _{TT}	V _{REF} -40 mV	V _{REF}	V _{REF} +40 mV	V	
Input voltage		V _i	0	_	V _{cc}	V	
AC high leve	l input voltage	V _{IH}	V_{REF} +310 mV	_	_	V	D
AC low level	input voltage	V _{IL}	_	_	V _{REF} -310 mV	V	D
DC high leve	l input voltage	V _{IH}	V_{REF} +150 mV	_	_	V	D
DC low level	input voltage	V _{IL}	_	_	V_{REF} –150 mV	V	D
High level inp	out voltage	V _{IH}	1.7	_	V _{DDQ} +0.3	V	RESET
Low level inp	ut voltage	V _{IL}	-0.3	_	0.7	V	RESET
Differential	(Common mode range)	V _{CMR}	0.97	_	1.53	V	CLK, CLK
input voltage	(Minimum peak to peak input)	V_{PP}	360	_	_	mV	CLK, CLK
High level ou	tput current	I _{OH}	_	_	-20	mA	
Low level out	tput current	I _{OL}	_	_	20	mA	
Operating ter	mperature	Та	0	_	70	°C	

Note: The RESET input of the device must be held at V_{DDQ} or GND to ensure proper device operation. The differential inputs must not be floating, unless RESET is low.

Logic Diagram



Electrical Characteristics

Item		Symbol	$V_{cc}(V)$	Min	Тур	Max	Unit	Test Conditions
Input diode volta	age	V _{IK}	2.3	_	_	-1.2	V	$I_{IN} = -18 \text{ mA}$
Output voltage		V _{OH}	2.3 to 2.7	V _{cc} -0.2	_	_	V	$I_{OH} = -100 \ \mu A$
			2.3	1.95	_	$V_{\scriptscriptstyle DDQ}$	-	I _{oH} = −16 mA
		V _{OL}	2.3 to 2.7	_	_	0.2	=	$I_{OL} = 100 \mu A$
			2.3	0	_	0.35	_	I _{OL} = 16 mA
Input current	(All inputs)	I _{IN}	2.7	_	_	±5	μΑ	V _{IN} = 2.7 V or 0
Quiescent supp	ly current	I _{CC} *2	2.7	_	25	45	mA	$V_{IN} = V_{IH(AC)}$ or $V_{IL(AC)}$, $I_O = 0$
Standby current		CC (stdy)	2.7	_	_	10	μΑ	RESET = GND
Dynamic operat	ing clock only	I _{CCD} *2	2.7	_	38	45	clock	$\label{eq:RESET} \hline \hline \textbf{RESET} = \textbf{V}_{\text{CC}}, \\ \textbf{V}_{\text{J}} = \textbf{V}_{\text{IH}(\text{AC})} \text{ or } \textbf{V}_{\text{IL}(\text{AC})}, \\ \textbf{CLK and CLK switching 50\%} \\ \textbf{duty cycle} \\ \hline$
Dynamic operat data input	ing per each	I _{CCD} *2	2.7	_	11	15	clock MHz / data	$\label{eq:RESET} \hline \textbf{RESET} = \textbf{V}_{\text{CC}}, \\ \textbf{V}_{\text{I}} = \textbf{V}_{\text{IH}(\text{AC})} \text{ or } \textbf{V}_{\text{IL}(\text{AC})}, \\ \textbf{CLK and } \hline \textbf{CLK} \text{ switching 50\%} \\ \text{duty cycle. One data input switching at half clock} \\ \text{frequency, 50\% duty cycle.} \\ \hline \\ \hline \end{tabular}$
Output high *3		r _{oh}	2.3 to 2.7	7	_	20 *4	Ω	I _{OH} = -20 mA
Output low *3		r _{ol}	2.3 to 2.7	7	_	20 *4	Ω	I _{OL} = 20 mA
r _{OH} - r _{OL} each separate bit '3		$r_{o(\Delta)}$	2.5	_	_	4	Ω	I_{\circ} = 20 mA, Ta = 25°C
Input	Data inputs	C _{IN}	2.5 *1	2.5	_	3.5	pF	$V_{I} = V_{REF} \pm 310 \text{ mV}$
capacitance	CLK and CLK	•		2.5	_	3.5	-	$V_{CMR} = 1.25 \text{ V}, V_{PP} = 360 \text{ mV}$
	RESET				3.0		_	$V_{i} = V_{cc}$ or GND

Notes: 1. All typical values are at $V_{cc} = 2.5 \text{ V}$, $Ta = 25^{\circ}\text{C}$.

- 2. Total I_{cc} (max) = I_{cc} + { I_{ccd} (clock)×f(clock)} + { I_{ccd} (Data)×1/2f(clock)×14}
- 3. This is effective in the case that it did terminate by resistance.
- 4. See figure. 1, 2.

Switching Characteristics

Item		Symbol	V_{cc} = 2.5 ± 0.2 V		Unit	Test Condition	
			Min	Max			
Clock frequency *1		f _{clock}	_	200	MHz		
Setup time	Fast slew rate *4,6	t _{su}	0.75	_	ns	Data before CLK↑, CLK↓	
	Slow slew rate *5, 6	_	0.9	_	<u> </u>		
Hold time	Fast slew rate *4,6	t _h	0.75	_	ns	Data after CLK↑, CLK↓	
	Slow slew rate *5, 6	_	0.9	_	_		
Differential inputs active time		t _{act}	22	_	ns	Data inputs must be low after RESET high.	
Differential inputs inactive time		t _{inact}	22	_	ns	Data and clock inputs must be held at valid levels (not floating) after RESET low.	
Pulse width		t _w	2.5	_	ns	CLK, CLK "H" or "L"	
Output slew *3		t _{sl}	1	4	volt/ns		

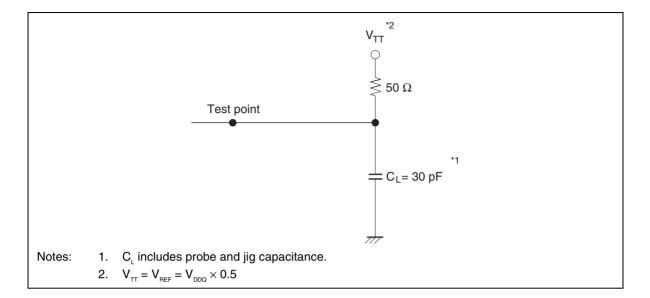
$$(C_{\scriptscriptstyle L} = 30 \text{ pF}, \, R_{\scriptscriptstyle L} = 50 \; \Omega, \, V_{\scriptscriptstyle REF} = V_{\scriptscriptstyle TT} = V_{\scriptscriptstyle DDQ} \times 0.5)$$

Item	Symbol	$V_{cc} = 2.5 \pm 0.2 \text{ V}$			Unit	FROM	то
		Min	Тур	Max		(Input)	(Output)
Maximum clock frequency	f _{max}	200	_	_	MHz		
Propagation delay time *2	t _{PLH,} t _{PHL}	1.1	_	2.8	ns	CLK, CLK	Q
	t _{phi}	_	_	5.0		RESET	Q

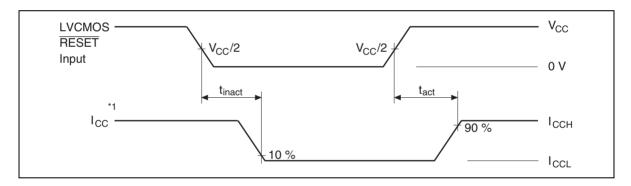
Notes: 1. Although the clock is differential, all timing is relative to CLK going high and CLK going low.

- 2. This timing relationship is specified into test load (see waveforms 3, 4) with all of the outputs switching.
- 3. Assumes into an equivalent, distributed load to the address net structure defined in the application information provided in this specification.
- 4. For data signal input slew rate \geq 1 V/ns.
- 5. For data signal input slew rate ≥ 0.5 V/ns and < 1 V/ns.
- 6. CLK, $\overline{\text{CLK}}$ signals input slew rates are ≥ 1 V/ns.

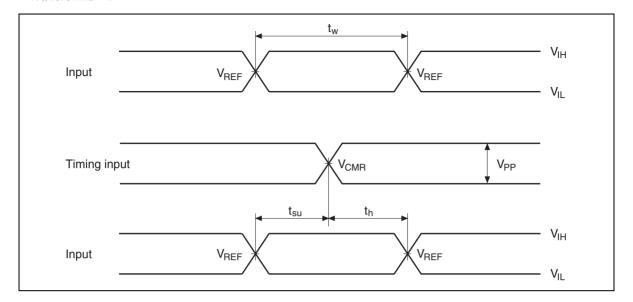
Test Circuit



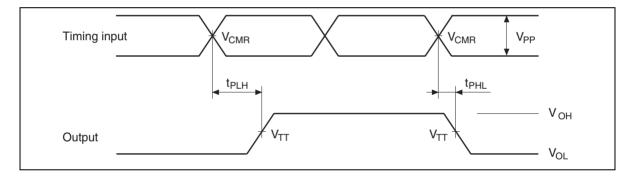
Waveforms – 1



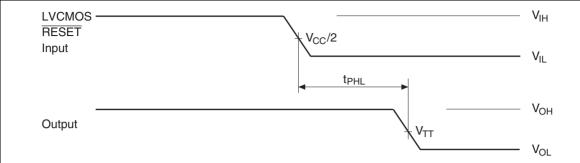
Waveforms - 2



Waveforms – 3



Waveforms - 4



Notes:

- 1. I_{cc} tested with clock and data inputs held at V_{cc} or GND, and $I_{o} = 0$ mA.
- 2. All input pulses are supplied by generators having the following characteristics : PRR \leq 10 MHz, Zo = 50 Ω , input slew rate = 1 V/ns \pm 20% (unless otherwise specified).
- 3. The outputs are measured one at a time with one transition per measurement.
- 4. $V_{TT} = V_{REF} = V_{DDQ}/2$
- 5. $V_{IH} = V_{REF} + 310 \text{ mV}$ (AC voltage levels) for differential inputs. $V_{IH} = V_{CC}$ for LVCMOS input.
- 6. $V_{\parallel} = V_{BFF} 310 \text{ mV}$ (AC voltage levels) for differential inputs. $V_{\parallel} = \text{GND}$ for LVCMOS input.
- 7. t_{PLH} and t_{PHL} are the same as t_{pd}

Application Data

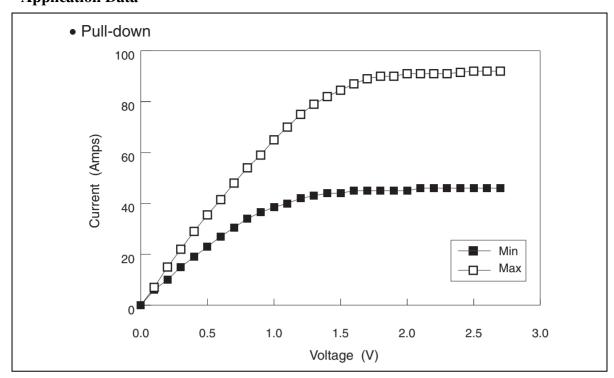


Figure. 1

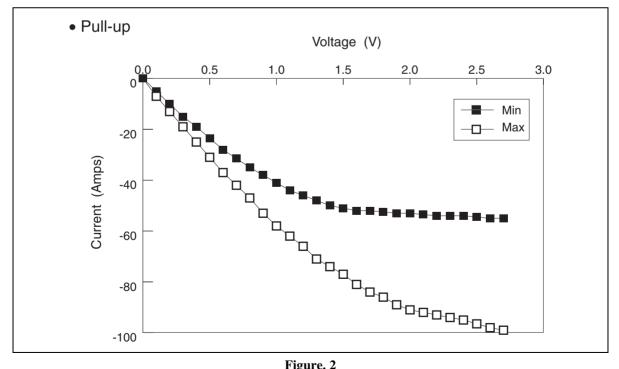
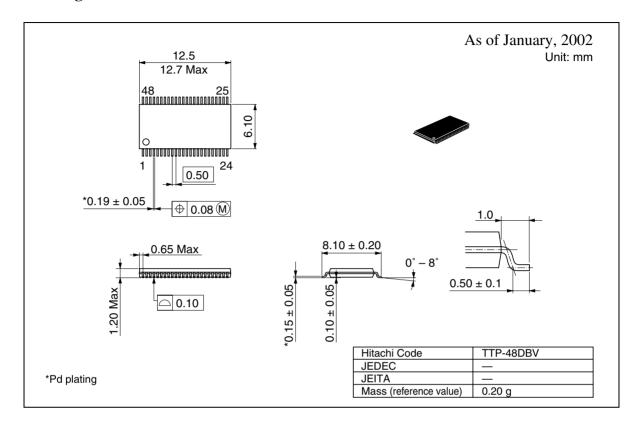


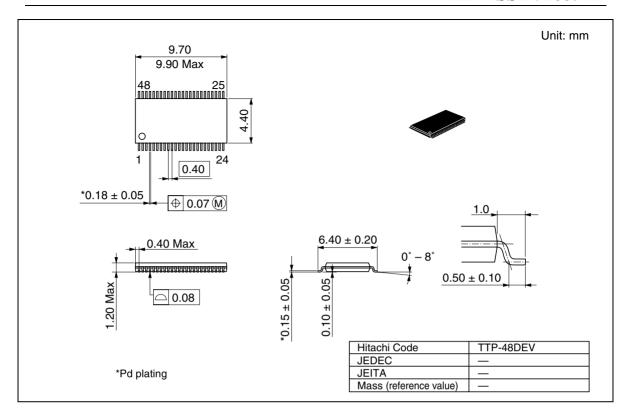
Figure. 2

Curve Data

Voltage (V)	Pull-down		Pull-up	Pull-up			
	I (mA)	I (mA)	I (mA)	I (mA)			
	Min	Max	Min	Max			
0.0	0	0	0	0			
0.1	6	7	-6	-7			
0.2	11.5	15	-11.5	-13			
0.3	16	22	-16	-19			
0.4	20	29	-20	-25			
0.5	23	35.5	-23.5	-31			
0.6	27	41.5	-28	-37			
0.7	30.5	48	-31.5	-42			
0.8	34	54	-35	-47			
0.9	36.5	59	-38	-53			
1.0	38.5	65	-41	-58			
1.1	40	70	-44	-62			
1.2	42	75	-46	-66			
1.3	43	79	-48	-71			
1.4	44	82	-50	-74			
1.5	44	84.5	– 51	-77			
1.6	45	87	- 52	-81			
1.7	45	89	-52	-84			
1.8	45	90	-52.5	-86			
1.9	45	90	-53	-89			
2.0	45	91	-53	-91			
2.1	46	91	-53.5	-92			
2.2	46	91	-54	-93			
2.3	46	91	-54	-94			
2.4	46	91.5	-54	- 95			
2.5	46	92	-54.5	-96.5			
2.6	46	92	- 55	-98			
2.7	46	92	-55	-99			

Package Dimensions





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